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Application/Control No.	Applicant(s)/Patent under Reexamination	
09/843,197	CHIU ET AL.	
Examiner	Art Unit	
Cong-Lac Huynh	2178	

	SEARCHED			
Class	Subclass	Date	Examiner	
715	530	8/28/2006	CLH	
	500	8/28/2006	CLH	
	732	8/28/2006	CLH	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
	<u> </u>		

S (INCLUDIN	EARCH NOT	ES STRATEGY)
		DATE	EXMR
East		8/28/2006	CLH
ACM		8/28/2006	CLH